

## IRFP250MPbF

IR MOSFET™

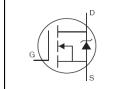
## Features

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

## Description

IR MOSFET<sup>™</sup> technology from Infineon utilizes advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and rugged device design that IR MOSFET<sup>™</sup> devices are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercialindustrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.



V <sub>(BR)DSS</sub>	200V
R <sub>DS(on)</sub> max.	0.075Ω
ID	30A



G	D	S
Gate	Drain	Source

Base part number	Packago Typo	Standard Pack		Orderable Part Number
Base part number	Package Type	Form	Quantity	Olderable Fait Nulliber
IRFP250MPbF	TO-247AD	Tube	25	IRFP250MPbF

## **Absolute Maximum Ratings**

Symbol Parameter		Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	30	
$I_D @ T_C = 100^{\circ}C$ Continuous Drain Current, $V_{GS} @ 10V$		21	Α
I <sub>DM</sub> Pulsed Drain Current ①⑤		120	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	214	W
	Linear Derating Factor	1.4	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy 25	315	mJ
I <sub>AR</sub> Avalanche Current ①⑤		30	A
E <sub>AR</sub> Repetitive Avalanche Energy ①		21	mJ
dv/dt	Peak Diode Recovery dv/dt3	8.6	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range	-55 10 + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

## Thermal Resistance

Symbol Parameter		Тур.	Max.	Units
$R_{ ext{ heta}JC}$	Junction-to-Case		0.7	
$R_{ hetaCS}$	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
$R_{ ext{ heta}JA}$	Junction-to-Ambient		40	



## Electrical characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	200			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.26		V/°C	Reference to $25^{\circ}$ C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.075	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 18A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	17			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 18A④
1	Drain-to-Source Leakage Current			25		V <sub>DS</sub> = 200V, V <sub>GS</sub> = 0V
IDSS	Dialit-to-Source Leakage Guitelli			250	μA	V <sub>DS</sub> = 160V,V <sub>GS</sub> = 0V,T <sub>J</sub> =150°C
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
IGSS	Gate-to-Source Reverse Leakage			-100	ПА	V <sub>GS</sub> = -20V

## Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Demonstern	N.4.:	<b>T</b>	N/	1.1.0.14.0	O a waliti a wa
Diode Cl	naracteristics					
C <sub>rss</sub>	Reverse Transfer Capacitance		83			<i>f</i> = 1.0MHz, See Fig.5
C <sub>oss</sub>	Output Capacitance		315		pF	V <sub>DS</sub> = 25V
C <sub>iss</sub>	Input Capacitance		2159			V <sub>GS</sub> = 0V
L <sub>S</sub>	Internal Source Inductance		13			from package
L <sub>D</sub>	Internal Drain Inductance		5.0			Between lead, 6mm (0.25in.)
t <sub>f</sub>	Fall Time		33			$R_{D}$ = 5.5 $\Omega$ , See Fig.10④
t <sub>d(off)</sub>	Turn-Off Delay Time		41		115	R <sub>G</sub> = 3.9Ω
t <sub>r</sub>	Rise Time		43		ns	I <sub>D</sub> = 18A
t <sub>d(on)</sub>	Turn-On Delay Time		14			V <sub>DD</sub> = 100V
$Q_{gd}$	Gate-to-Drain Charge			57		$V_{GS}$ = 10V, See Fig.6 and 13 $\oplus$
$Q_{gs}$	Gate-to-Source Charge			21	nC	V <sub>DS</sub> = 160V
$Q_{g}$	Total Gate Charge			123		I <sub>D</sub> = 18A

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			30		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			120		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_{J} = 25^{\circ}C, I_{S} = 18A, V_{GS} = 0V ④$
t <sub>rr</sub>	Reverse Recovery Time		186	279	ns	T <sub>J</sub> = 25°C ,I <sub>F</sub> = 18A
Q <sub>rr</sub>	Reverse Recovery Charge		1.3	2.0	μC	di/dt = 100A/µs ④

#### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).

 $\ensuremath{{}^{\circ}}$  Starting T<sub>J</sub> = 25°C, L = 1.9mH, R<sub>G</sub> = 25 $\Omega$ , I<sub>AS</sub> = 18A.(See fig. 12).

 $\label{eq:ISD} \label{eq:ISD} \begin{tabular}{ll} \Im & I_{SD} \leq 18A, \, di/dt \leq 374A/\mu s, \, V_{DD} \leq V_{(BR)DSS}, \, T_J \leq 175^\circ C. \end{tabular} \end{tabular}$ 

④ Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%.



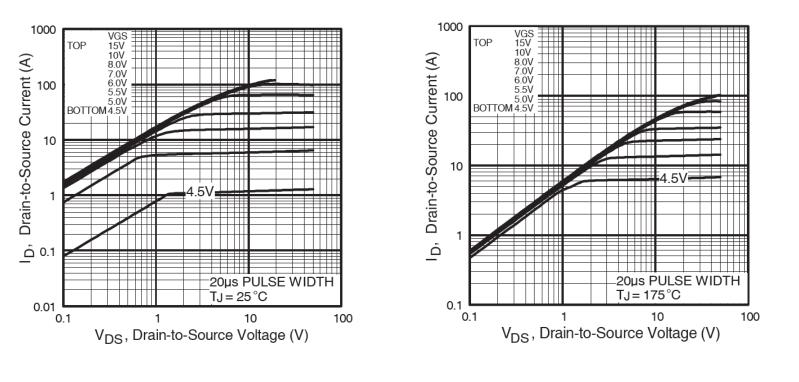


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

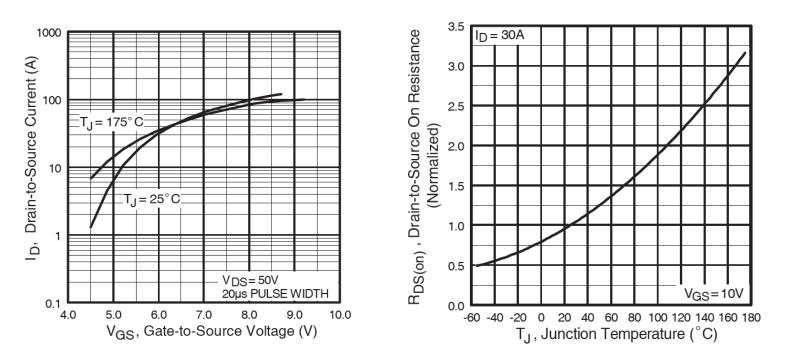
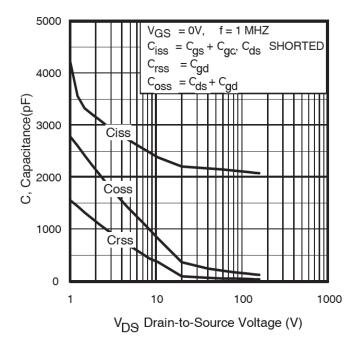
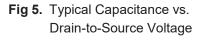
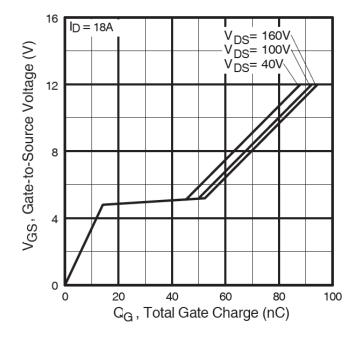


Fig. 3 Typical Transfer Characteristics











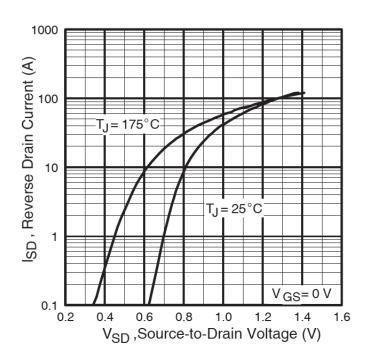


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

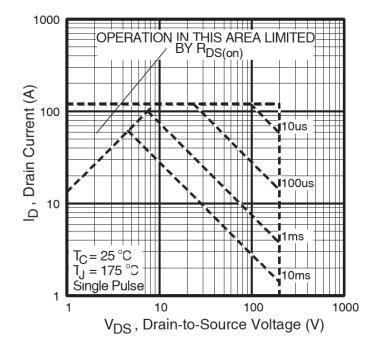


Fig 8. Maximum Safe Operating Area



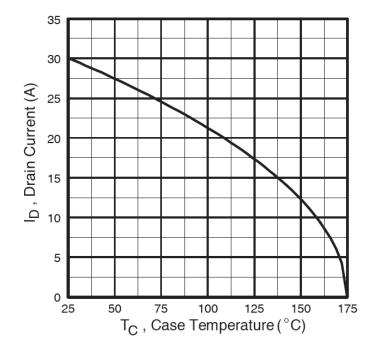


Fig 9. Maximum Drain Current vs. Case Temperature

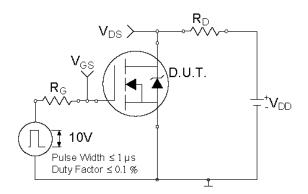


Fig 10a. Switching Time Test Circuit

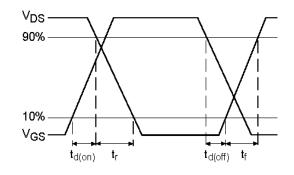


Fig 10a. Switching Time Waveforms

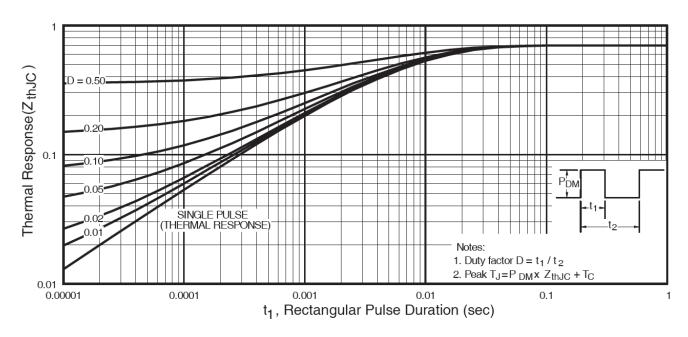


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

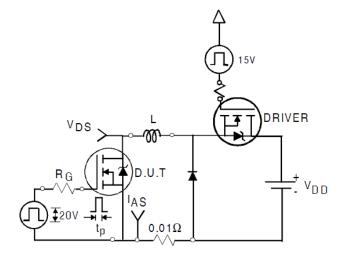


Fig. 12a. Unclamped Inductive Test Circuit

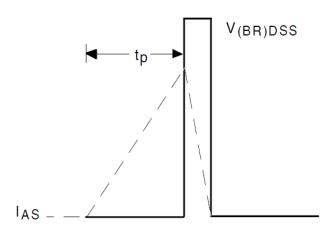


Fig. 12b. Unclamped Inductive Waveforms

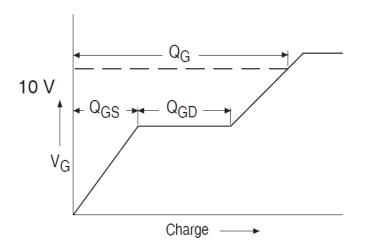


Fig 13a. Basic Gate Charge Waveform

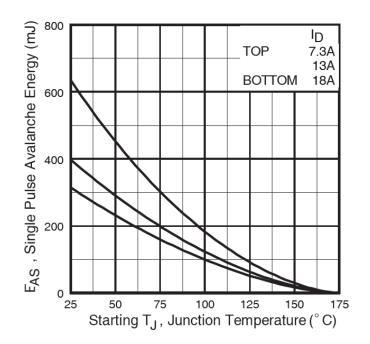


Fig 12c. Maximum Avalanche Energy vs. Drain Current

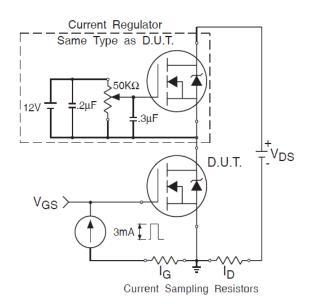
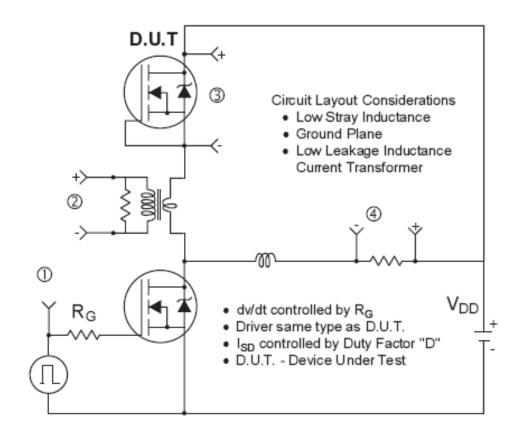
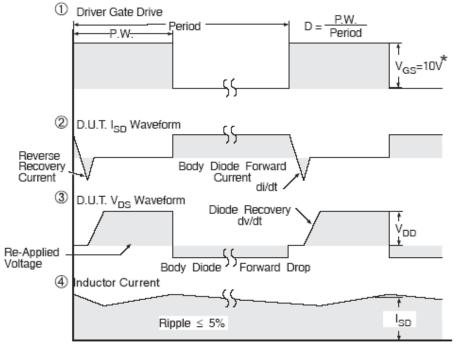


Fig 13b. Gate Charge Test Circuit



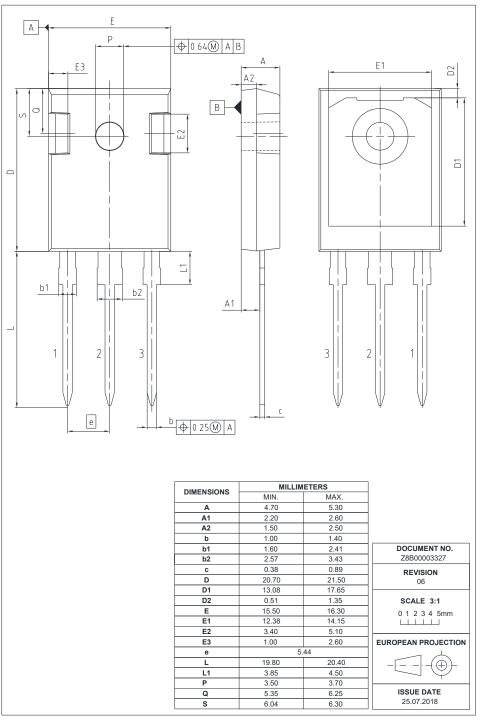


\*  $V_{GS}$  = 5V for Logic Level Devices

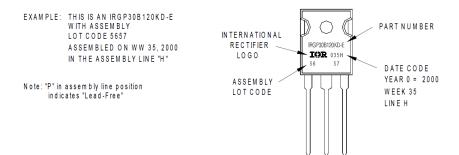
Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel IR MOSFET™



## TO-247AD Package Outline (Dimensions are shown in millimeters (inches))



## **TO-247AD Part Marking Information**





## **Revision History**

Date	Comments			
05/28/2020	<ul> <li>Updated datasheet with corporate template</li> <li>Updated Package picture-page1</li> <li>Corrected from "Hexfet power MOSFET" to " IR MOSFET™" -page1 &amp;7</li> <li>Corrected part marking from TO-247AC to TO-247AD on page 8.</li> </ul>			

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